

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/088,789	<b>Applicant(s)/Patent under Reexamination</b> BAITZ ET AL.
	<b>Examiner</b> Seung H. Lee	<b>Art Unit</b> 2876

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
Same as	Above	10/27/2006	SL